

Product Description

The best AFM tips for routine measurements at the reasonable price!

Unique probes with Single Crystal Full Diamond tip for topography measurements.

Nominal values: force constant – 3.5 N/m, resonance frequency – 140 kHz.

Probe highlights:

- The probes are highly resistant to mechanical destructions and keep their sharpness during the whole working day and more!
- These probes enable highly repeatable high resolution operation to ensure you consistently get the best possible data from your system.
- Diamond tips are less sensitive to static charges on sample's surface. That results in easy approach and more detailed topography imaging in comparison with Si cantilevers in the same conditions.
- Due to the hydrophobic surface the diamond tip doesn't get dirty while scanning samples (biological etc.).

Diamond tip specifications

Geometry:	Cone
Tip radius:	< 10nm
Tip height (h):	10-15 μ m
Tip material:	Single crystal diamond
Cone angle:	< 25°

General Features

Material	Polysilicon cantilever, full diamond tip
Chip size	3.6x1.6x0.4mm
Reflective side coating	Au
Tip coating	No
Tip curvature radius	< 10nm

Special Features

Cantilever series	Cantilever length, $L \pm 2 \mu$ m	Cantilever width, $W \pm 3 \mu$ m	Cantilever thickness, $T \pm 0.15 \mu$ m	Resonant frequency, kHz			Force constant, N/m		
				min	typical	max	min	typical	max
HA_NC/FD	124	34	1.85	125	140	155	2.5	3.5	4.5